

# Comments and Corrections

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## Corrections to “Pulsed Measurements Based Investigation of Trap Capture and Emission Processes in CNTFETs”

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In [1], caption of Fig. 3(a),  $e - 3$  should read  $10^{-3}$  as below.

$$\Delta t_j / ms = (10^{-3}, 3, 14, 65)$$

### REFERENCES

- [1] C. Weimer, A. Pacheco-Sánchez, J. Trommer, and M. Schröter, “Pulsed measurements based investigation of trap capture and emission processes in CNTFETs,” *IEEE Trans. Nanotechnol.*, vol. 20, pp. 459–465, May 2021.

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